

FIG. 1

DETERMINING A CHANGE OF A TEMPERATURE SENSITIVE PARAMETER OF THE CHIP THAT IS PREDICTABLE WITH TEMPERATURE WITH CHANGE OF TEMPERATURE 12 MEASURING THE TEMPERATURE SENSITIVE PARAMETER OF THE CHIP DURING TESTING OF THE CHIP 14 MEASURING THE CHIP TEMPERATURE DIRECTLY DURING OR FOLLOWING THE MEASUREMENT OF THE TEMPERATURE SENSITIVE PARAMETER 16 DETERMINING AN ADJUSTED TEMPERATURE SENSITIVE PARAMETER OF THE CHIP BASED UPON THE MEASURED TEMPERATURE SENSITIVE PARAMETER OF THE CHIP DURING TESTING, THE MEASURED CHIP TEMPERATURE, AND THE DETERMINED CHANGE OF THE TEMPERATURE SENSITIVE PARAMETER OF THE CHIP WITH TEMPERATURE 18 SORTING AND CLASSIFYING INDIVIDUAL PRODUCT CHIP MODULES INTO SEVERAL DIFFERENT SORTS/CATEGORIES 20